Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a SOT186A (TO-220F) "full pack" plastic package intended for use in circuits where high static and dynamic dV/dt and high dl/dt can occur. This "series CT" triac will commutate the full RMS current at the maximum rated junction temperature ($T_{\text{j(max)}}$) = 150 °C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

2. Features and benefits

- · 3Q technology for improved noise immunity
- 2500V RMS isolation voltage capability
- · High commutation capability with maximum false trigger immunity
- High immunity to false turn-on by dV/dt
- · High junction operating temperature capability
- · High voltage capability
- · High current capability
- · Isolated mounting base package
- · Least sensitive gate for highest noise immunity
- · Planar passivated for voltage ruggedness and reliability
- Triggering in three quadrants only
- UL1557 certified (Document number E346397)

3. Applications

- Applications subject to high temperature
- Heating controls
- High power motor control
- High power switching

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes		Values		Unit
V_{DRM}	repetitive peak off-state voltage				800		V
I _{T(RMS)}	RMS on-state current	full sine wave; T _h ≤ 42 °C; <u>Fig. 1</u> ; <u>Fig. 2</u> ; <u>Fig. 3</u>		30			А
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5		270			А
		full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms			297		Α
T _j	junction temperature				150		°C
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;}$ $T_j = 25 \text{ °C; } Fig. 7$		-	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 ^{\circ}\text{C; } Fig. 7$		-	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2- \text{ G-;}$ $T_j = 25 \text{ °C; } Fig. 7$		-	-	35	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	50	mA
V _T	on-state voltage	I _T = 42 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.20	1.55	V

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Dynamic	characteristics						
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		2000	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		1000	-	-	V/µs
dI _{com} /dt	rate of change of commutating current	V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/ μ s; gate open circuit		16	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 30 \text{ A};$ $dV_{com}/dt = 20 \text{ V}/\mu\text{s}; gate open circuit}$		13		-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1	mb	orași in contra de la contra del contra de la contra de la contra de la contra de la contra de l
2	T2	main terminal 2		T2————————————————————————————————————
3	G	gate		K G
mb	n.c	mounting base; isolated		sym051
			1 2 3	

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	3 - 3	Package issue date
BTA330X-800CT	TO220F	BTA330X-800CTQ	Tube	50	SOT186A	14-Nov-2013

7. Marking

Table 4. Marking codes

Type number	Marking codes
BTA330X-800CT	BTA330X 800CT

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
V_{DRM}	repetitive peak off-state voltage			800	V
V_{RRM}	repetitive peak reverse voltage			800	V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_h \le 42 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3		30	А
I _{TSM}	non-repetitive peak on-state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig 4; Fig 5		270	А
		full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms		297	Α
l ² t	I ² t for fusing	t _p = 10 ms; SIN		364.5	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 70 mA		100	A/µs
I _{GM}	peak gate current			2	А
P_GM	peak gate power	$T_{j(init)}$ = 25 °C; t_p = 20 µs		5	W
$P_{G(AV)}$	average gate power	over any 20 ms period		0.5	W
T _{stg}	storage temperature			-40 to 150	°C
T _j	junction temperature			150	°C

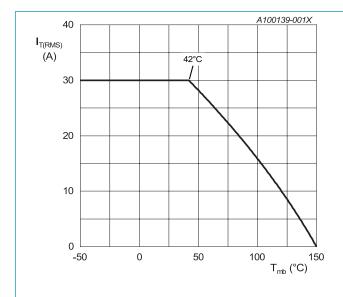


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

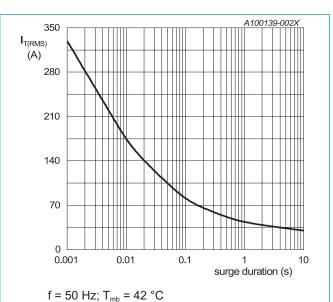


Fig. 2. RMS on-state current as a function of surge duration; maximum values

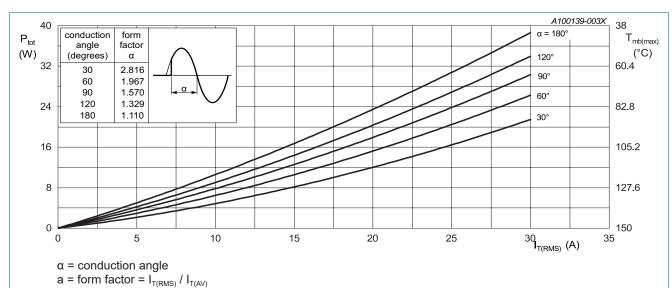


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

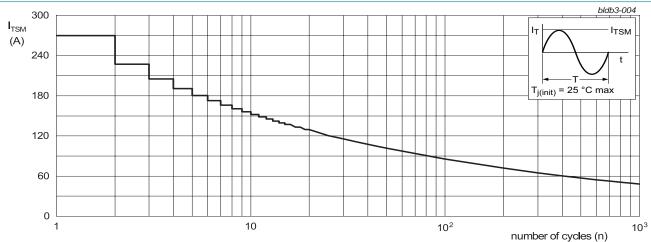
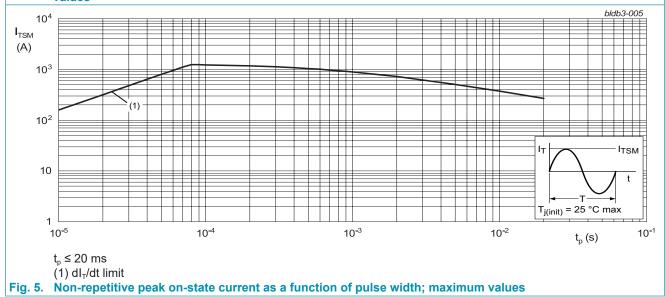


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



f = 50 Hz

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
$R_{\text{th(j-mb)}}$	thermal resistance from junction to heatsink	Fig. 6		-	-	2.8	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient	in free air		-	55	-	K/W

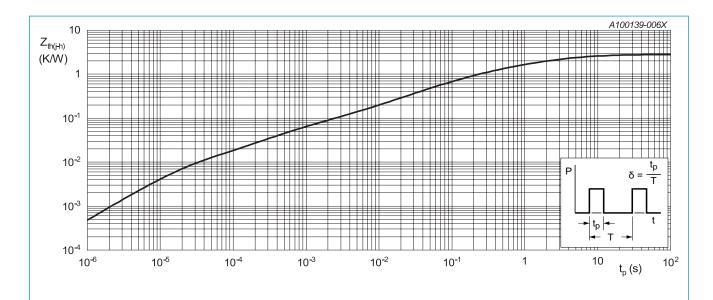


Fig. 6. Transient thermal impedance from junction to heatsink as a function of pulse duration; maximum values

10. Isolation characteristics

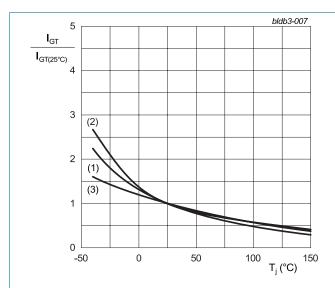
Table 7. Isolation characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	from all pins to external heatsink; sinusoidal waveform; clean and dust free; $50 \text{ Hz} \le f \le 60 \text{ Hz}$; RH $\le 65 \%$; T _h = $25 ^{\circ}\text{C}$		-	-	2500	V
C _{isol}	isolation capacitance	from main terminal 2 to external heatsink; $f = 1 \text{ MHz}$; $T_h = 25 ^{\circ}\text{C}$		-	10	-	pF

11. Characteristics

Table 8. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+; T_j = 25 °C; Fig. 7$		-	-	35	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G-; $ $T_j = 25 \text{ °C}; Fig. 7$		-	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; Fig. 7}$		-	-	35	mA
I _L	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2+ G+};$ $T_j = 25 \text{ °C}; \text{ Fig. 8}$		-	-	70	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2+ G-};$ $T_j = 25 \text{ °C}; \text{ Fig. 8}$		-	-	100	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \text{ Fig. 8}$		-	-	70	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	50	mA
V _T	on-state voltage	I _T = 42 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.20	1.55	V
V_{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11		-	0.9	1.3	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 ^{\circ}\text{C}$		0.20	0.45	-	V
I _D	off-state current	V _D = 800 V; T _j = 25 °C		-	-	10	μA
		V _D = 800 V; T _j = 150 °C		-	0.4	2	mA
I _R	reverse current	V _R = 800 V; T _j = 25 °C		-	-	10	μΑ
		V _R = 800 V; T _j = 150 °C		-	0.4	2	mA
Dynamic	characteristics						1
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		2000	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		1000	-	-	V/µs
dI _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 30 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; gate open circuit}$		16	-	-	A/ms
		$V_D = 400 \text{ V; } T_j = 150 \text{ °C; } I_{T(RMS)} = 30 \text{ A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; gate open circuit}$		13		-	A/ms



- (1) T2- G-
- (2) T2+ G-
- (3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

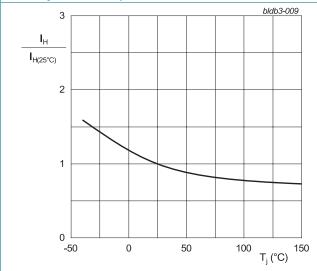


Fig. 9. Normalized holding current as a function of junction temperature

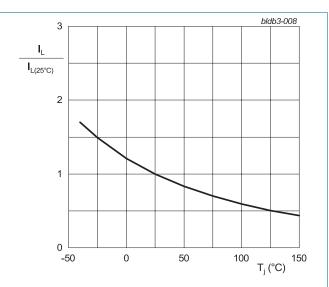
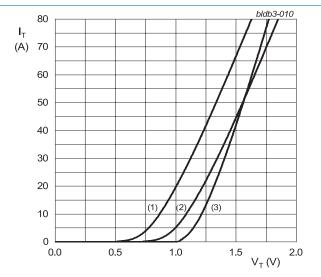


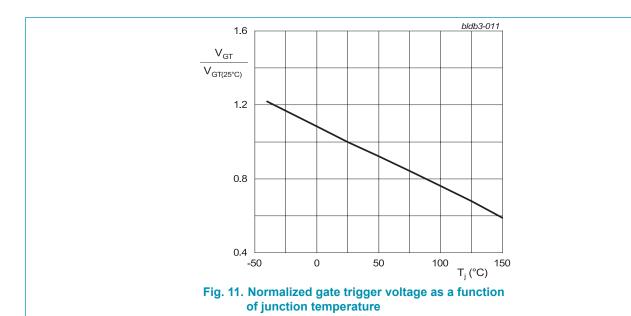
Fig. 8. Normalized latching current as a function of junction temperature



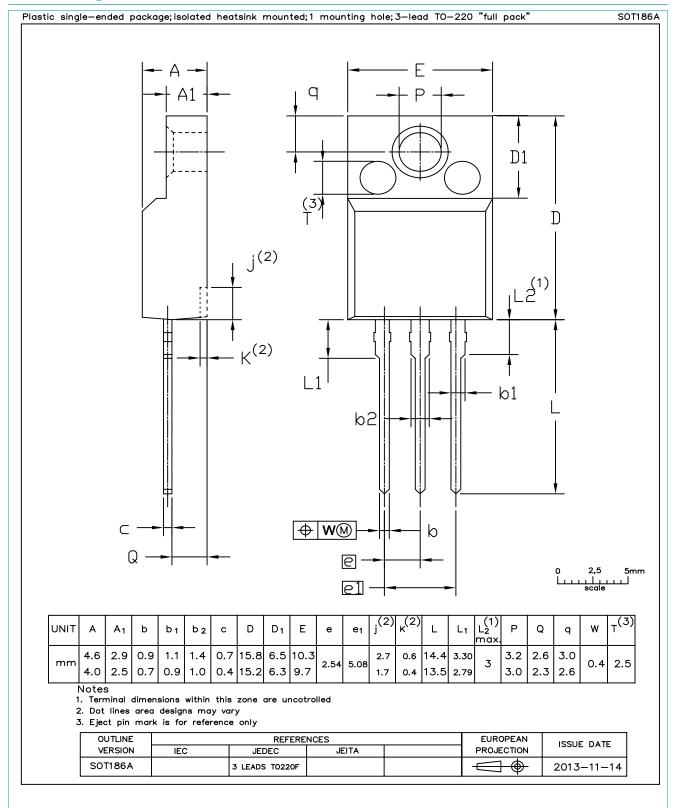
 $V_o = 1.049 \text{ V}; R_s = 0.0114 \Omega$

- (1) T_i = 150 °C; typical values
- (2) T_i = 150 °C; maximum values
- (3) $T_j = 25$ °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



12. Package outline



13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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For more information, please visit: http://www.ween-semi.com
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